# Eureka2s

## LP-DDR2 . LP-DDR3
## Memory Chip Tester

The Eureka2s Memory Chip Tester is specially designed to test DRAM, LPDRAM, NAND, NOR, EEprom, and eMMC in their BGA, eMCP or POP packages. It provides 128 DQ bits for testing up to 4 pieces of 32 bit chips simultaneously.

It has many features including advance "Error Capture", "Shmoo Plot", "Power Consumption Analysis" as well as refresh performance test at extreme temperatures.*

*Optional Heat Chamber Required

### Flexible
Test different devices by change DUT module.

### High Performance
Reaching 1600MHz top data speed.

### Easy to Use
Windowed GUI software is user-friendly and self-driven.

### Confidence
Catches functional and excessive power problems.

www.simtester.com

For more than three decades, CST, Inc. has helped to keep computer systems up and running worldwide by designing, manufacturing and supplying affordable memory testers. CST's memory testing products have become internationally recognized by the computer and computer memory industry.

With progressive engineering and state-of-the-art technology, the Eureka2s Memory Chip Test System was created to be the next industry test standard for DRAM and Mobile Chip testing.

# Eureka2s
## *LP-DDR2 . LP-DDR3* Memory Chip Tester

# FEATURES

## HIGH PERFORMANCE SYSTEM

- Auto ID : Chip Type
- Auto ID : Memory Configuration,Size
- Auto ID : Frequency, Cas Latency
- Detects : Manufacturers ID
- Real Cycle Time Testing
- Super Fast Test Time

## EFFECTIVE TEST ALGORITHM

- Quick Checks for Assembly faults
- Up to 27 Test Patterns for Functional Tests
- Complete SHMOO Plot Standard
- Fault Focusing Tools to Detect Bad Chips
- Support Heat Chamber (Optional)
- Graphical Error Capture Standard

## EASE OF USE

- Interface with Desktop via USB Port
- Window-Driven Graphic System
- Pictorial Aid to Pinpoint Faulty Chip
- EZ Firmware Upgrade
- Support Most Automatic Chip Handlers
- Support Window XP, VISTA & Win7

# SPECIFICATIONS

| | |
|---|---|
| Clock Frequency | : 266, 333, 400, 533, 667, 800 Mhz |
| Data Rate | : 533, 667, 800, 1066, 1333,1600 Mhz |
| Address Depth | : 4 Gigawords Capacity up to 16Row x16Col |
| Data Width | : 128 Bits |
| Voltage | : 0.8 - 3.3V @ 10mV step |
| CAS Latency | : 4, 5, 6, 7, 8, 9 & 11 Clock |
| Trcd & Trp | : 4, 5, 6, 7, 8, 9 & 11 Clock |
| Burst Length | : 4 & 8 |
| CAS Write | : 4, 5, 6, 7, 8 & 9 |
| Mirror-Mode | : Auto |
| Dynamic ODT | : Auto , 40, 60, 120 ohm |
| ZQ Adjust | : Auto Calibrate |
| Refresh Cycle | : Auto / Self Refresh |
| Open/Short | : Walk Data, Address, CS, CKE, DQM, DQS Test |
| AC Test Pattern | : Mat-S, March B, March X, March Y, March G, March U, Mov-I, Hammer Read Test |

## GENERAL SPECS

| | |
|---|---|
| Power Requirement | : 110 V - 230 VAC |
| Operating Temp | : -20 to 100 Degrees F |
| Humidty | : 20% to 80% , Non-Condensing |
| Dimension | : 432 X 316 X 192 mm - 25 Pounds |
| Host Computer | : Intel /AMD Based ( USB 1.1, 2.0 & 3.0) |

All LP-DDR2, LPDDR3, and LP-DDR DUT modules are made to customer requirements; call CST for pricing.